



INFORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL TO THE
PROSECUTION OF THE SUBJECT APPLICATION

Applicants: S. Ohkawa et al. Attorney Docket No. SUSU121258
Application No.: 10/600,800 Group Art Unit: 2858
Filed: June 19, 2003
Title: SEMICONDUCTOR CHARACTERISTIC EVALUATION APPARATUS

OTHER INFORMATION
(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Cite
Initial No.

Dr 01 Chen, J.C., et al., "An On-Chip, Interconnect Capacitance Characterization Method With Sub-Femto-Farad Resolution," *Proceedings of the IEEE, International Conference on Microelectronic Test Structures*, Monterey, California, Vol. 10, March 1997, pp. 77-80.

Examiner Date Considered
Donald J. Fair 8-10-04

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

JMS:snh

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